

Form PTO-449 (MODIFIED)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. 039153-0310 (F0797)	SERIAL NO. 09/819,552
INFORMATION DISCLOSURE CITATION  (Use several sheets if necessary)		APPLICANT Calvin T. Gabriel et al	GROUP ART UNIT 8124
		FILING DATE 03/28/2001	

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE
BT		09/819,342		Shields et al			03/28/01
		09/819,343		Gabriel et al			03/28/01
		09/819,344		Okoroanyanwu et al			03/28/01
		09/819,692		Okoroanyanwu et al			03/28/01
		09/820,143		Okoroanyanwu et al			03/28/01
		6,107,172	08/22/00	Yang et al	438	585	
		6,103,457	08/15/00	Gabriel	430	318	
		5,965,461	10/12/99	Yang et al	438	717	
		5,003,178	03/26/91	Livesay	250	492.300	

## FOREIGN PATENT DOCUMENTS

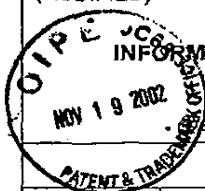
	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION	
							YES	NO

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

BT	Livesay, W. R., "Large-area electron-beam source," Journal of Vacuum Science & Technology B, Vol. 11, No. 6, Nov./Dec. 1993, pp. 2304-2308, American Vacuum Society
	Yang, J. J. et al, "Electron Beam Processing for Spin-on Polymers and its Applications to Back-End-of-Line (BEOL) Integration," Materials Research Society Symposium Proceedings, Vol. 511, 1998, pp. 49-55, Materials Research Society
BT	Ross et al, "Plasma Etch Characteristics of Electron Beam Processed Photoresist," The Society of Photo-Optical Instrumentation Engineers, Vol. 2438, 1995, pp. 803-816, SPIE-The International Society for Optical Engineering
	Grün, Von A. E., "Lumineszenz-photometrische Messungen der Energieabsorption im Strahlungsfeld von Elektronenquellen Eindimensionaler Fall in Luft," Zeitschrift für Naturforschung, Vol. 12a, 1957, pp. 89-95, Publisher: Zeitschrift für Naturforschung; full English Translation attached (11 pgs.)

EXAMINER Bin h Tran	DATE CONSIDERED 10/31/03
* EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include any copy of this form with next communication to applicant.	

Form PTO-1449 (MODIFIED)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. 039153-310 (F0797)	SERIAL NO. 09/819,552
<b>INFORMATION DISCLOSURE CITATION</b> (Please see several sheets if necessary)		APPLICANT Calvin T. Gabriel et al.	
		FILING DATE 03/28/2001	GROUP ART UNIT 2812

**U.S. PATENT DOCUMENTS**

EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE
BT	A1	6,232,048	5/15/2001	Buynoski et al.			
BT	A2	6,197,687	3/6/01	Buynoski			
↓	A3	6,110,837	8/29/00	Linliu et al.			
↓	A4	5,876,903	3/2/99	Ng et al.			
↓	A5	5,468,595	11/21/95	Livesay			
BT	A6	3,997,367	12/14/1976	Yau			

**FOREIGN PATENT DOCUMENTS**

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION	
							YES	NO

**OTHER DOCUMENTS** (Including Author, Title, Date, Pertinent Pages, Etc.)


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PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.

039153-0310 (F0797)

SERIAL NO.

09/819,552

## INFORMATION DISCLOSURE CITATION

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APPLICANT

Calvin T. Gabriel et al.

FILING DATE

03/28/2001

GROUP ART UNIT

2812

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE
BT	A1	6,197,687	3/06/2001	Buynoski		TC 2800 MAIL ROOM	RECEIVED NOV 21 2002
↓	A2	5,994,225	11/30/99	Liu et al.			
↓	A3	5,876,903	3/02/99	Ng et al.			
BT	A4	5,468,595	11/21/1995	Livesay			

## FOREIGN PATENT DOCUMENTS

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## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

BT	A5	Chiong K.G. et al. "Resist Contrast Enhancement in High Resolution Electron Beam Lithography", Journal of Vacuum Science and Technology: Part B, American Institute of Physics, New York, US, vol. 7, no. 6.				
BT	A6	Patent Abstracts of Japan, vol 1999, no. 09, 30 July 1999 (1999-07-30) & JP 11 097328 A (Toshiba Corp), 9 April 1999 (1999-04-09) abstract				

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INFORMATION DISCLOSURE CITATION  (Use several sheets if necessary)				APPLICANT Uzodinma Okoroanyanwu et al.				
				FILING DATE 03/28/2001		GROUP ART UNIT 2812		
<b>U.S. PATENT DOCUMENTS</b>								
EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE	
Bt	A1	6,420,097	07/16/2002	Pike et al.	430	313		
Bt	A2	6,395,447	05/28/2002	Ishii et al.	430	191		
	A3	6,358,670	03/19/2002	Wong et al.	430	296		
	A4	6,319,655	11/20/2001	Wong et al.	430	311		
	A5	6,200,903	03/13/2001	Oh et al.	438	705		
	A6	6,174,818	01/16/2201	Tao et al.	438	733		
	A7	5,962,195	10/05/1999	Yen et al.	430	316		
	A8	4,446,222	05/01/1984	Kress	430	307		
Bt	A9	4394,211	07/19/1983	Uchiyama et al.	156	628		
<b>FOREIGN PATENT DOCUMENTS</b>								
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							YES	NO
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				FILING DATE 03/28/2001		GROUP ART UNIT 2812		
<b>U.S. PATENT DOCUMENTS</b>								
EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE	
BT	A1	6,589,709	7/08/2003	Okoroanyanwu et al.	430	296		
	A2	6,444,381	9/03/2002	Singh et al.	430	30		
	A3	6,420,702	7/16/2002	Tripsas et al.	250	310		
	A4	6,143,666	11/07/2000	Lin et al.	438	725		
	A5	6,121,130	9/19/2000	Chua et al.	438	623		
	A6	5,928,821	7/27/1999	Garrity et al.	430	23		
	A7	5,783,366	7/21/1998	Chen et al.	430	311		
	A8	5,747,803	05/05/1998	Doong, Yih-Yuh	250	307		
	A9	5,510,216	04/23/1996	Calabrese et al.	430	16		
	BT	A10	5,242,864	09/07/1993	Fassberg et al.	438	701	
<b>FOREIGN PATENT DOCUMENTS</b>								
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							YES	NO
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